

# ***AOS Semiconductor Product Reliability Report***

**AOZ8005CI, rev 1**

**Plastic Encapsulated Device**

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***This AOS product reliability report summarizes the qualification result for AOZ8005CI.***

***Review of the electrical test results confirm that AOZ8005CI pass AOS quality and reliability requirements for product release. The continuous qualification testing and reliability monitoring program ensure that all outgoing products will continue to meet AOS quality and reliability standards.***

## Table of Contents:

- I. Product Description
- II. Package and Die information
- III. Qualification Test Requirements
- IV. Qualification Tests Result
- V. Quality Assurance Information

### I. Product Description:

The AOZ8005CI is a transient voltage suppressor array designed to protect high speed data lines from ESD and lightning. The product comes in RoHS compliant, SOT-23 package and is rated over a -40°C to +85°C ambient temperature range.

Absolute Maximum Ratings	
Parameter	
VP-VN	6V
Peak Pulse Current (Ipp), tp=8/20uS	5A
Peak Power Dissipation (8x20mS@ 25°C) SOT-23	TBD
Storage Temperature (Ts)	-65°C to +150°C
ESD Rating per IEC61000-4-2, contact <sup>(1)</sup>	±12kV
ESD Rating per IEC61000-4-2, air <sup>(2)</sup>	±15kV
ESD Rating per Human Body Model <sup>(2)</sup>	±15kV
Junction Temperature (Tj)	-40°C to +125°C

Notes:

(1) IEC-61000-4-2 discharge with  $C_{Discharge}=150pF$ ,  $R_{Discharge}=330\Omega$

(2) Human Body Discharge per MIL-STD-883, Method 3015  $C_{Discharge}=100pF$ ,  $R_{Discharge}=1.5k\Omega$

### II. Package and Die Information:

<b>Product ID</b>	AOZ8005CI
<b>Process</b>	UMC 0.5um 5/18V 2P3M process
<b>Package Type</b>	SOT-23
<b>Die</b>	UE003A3 (size: 716 x 616 um)
<b>L/F material</b>	Copper A194FH
<b>Die attach material</b>	84-3J epoxy
<b>Die bond wire</b>	Au, 1mil
<b>Mold Material</b>	MP8005CIH4
<b>Plating Material</b>	Pure Tin

### III. Qualification Tests Requirements

- 2 lots of AOZ8005CI up to 168 hrs of B/I for New Product release.
- 2 lots of package qual testing (PCT, 250 cycles TC) for SOT-23 for package release to manufacturing.

### IV. Qualification Tests Result

Test Item	Test Condition	Sample Size	Result	Comment
Pre-Conditioning	Per JESD 22-A113 85 C <sup>0</sup> /85%RH, 3 cyc reflow@260 °C	2 lot (82 /lot)	pass	Pkg. Qual by extension using AOZ8000C. Lot 1 (wafer lot# F162T.51-20, marking: A02), 82 units, passed pre-conditioning. Lot 2 (wafer lot# F162T.51-20, marking: A03), 82 units, passed pre-conditioning.
HTOL (pkg qual burn-in )	Per JESD 22-A108_B Vdd=6V Temp = 125 °C	2 lot (80 /lot)	pass	Pkg. Qual by extension using AOZ8000C. Lot 1 (wafer lot# F162T.51-20, marking: A02), 80 units, passed 500 hrs . Lot 2 (wafer lot# F162T.51-20, marking: A03), 80 units, passed 500 hrs .
HTOL (new UI_EPI process)	Per JESD 22-A108_B Vdd=6V Temp = 125 °C	2 lot (80 /lot)	pass	Lot 1 (wafer lot# FN2MT.01-12, marking: AC001), 80 units, passed 500 hrs . Lot 2 (wafer lot# FN646.03-4 marking: AC003), 80 units, passed 168 hrs .
HAST	'130 +/- 2 °C, 85%RH, 33.3 psi, at VCC min power dissipation	2 lot (60 /lot)	pass	Pkg. Qual by extension using AOZ8000C. Lot 1 (wafer lot# F162T.51-20, marking: A02), 60 units, passed HAST 100 hrs . Lot 2 (wafer lot# F162T.51-20, marking: A03), 60 units, passed HAST 100 hrs .
Temperature Cycle	'-65 °C to +150 °C, air to air (2cyc/hr)	2 lot (82 /lot)	pass	Pkg. Qual by extension using AOZ8000C. Lot 1 (wafer lot# F162T.51-20, marking: A02), 82 units, passed TC 500 cycles. Lot 2 (wafer lot# F162T.51-20, marking: A03), 82 units, passed TC 500 cycles.
Pressure Pot	121C, 15+/-1 PSIG, RH= 100%	2 lot (82 /lot)	pass	Pkg. Qual by extension using AOZ8000C. Lot 1 (wafer lot# F162T.51-20, marking: A02), 82 units, passed PCT 96 hrs. Lot 2 (wafer lot# F162T.51-20, marking: A03), 82 units, passed PCT 96 hrs.
ESD Rating	Per IEC-61000-4-2, contact	3 units	pass	Lot 1 (wafer lot# FN646.03-4 , marking: AC003 ), 3 units passed ±12kV
ESD Rating	Per IEC-61000-4-2, air	3 units	pass	Lot 1 (wafer lot# FN646.03-4 , marking: AC003 ), 3 units passed ±15kV
Latch-up	Per JESD78A	3 units	pass	Lot 1 (wafer lot# FN646.03-4 , marking: AC003 ), 3 units passed Latch-up.

*The qualification test results confirm that AOZ8005CI pass AOS quality and reliability requirements for product release.*



## **V. Quality Assurance Information**

Acceptable Quality Level for outgoing inspection: **0.1%** for electrical and visual. Guaranteed

Outgoing Defect Rate: **< 50 ppm**

Quality Sample Plan: conform to **Mil-Std-105D**